IEC QUALITY ASSESSMENT SYSTEM (IECQ)

For rules and details of the IECQ visit www.iecq.org

IECQ Certificate of Approval
Independent Testing Laboratory

IECQ Certificate No.:	**IECQ-L DEKRA 16.0002-05**	**Issue No.:**	**1**	**Status:**	**Draft**

Additional Site to Certification: IECQ-L DEKRA 16.0002 **Originally Issued: 2016/08/17**

Supersedes:		**Issue Date:**	2025/07/20	**Site Added:**	2025/07/20
CB Reference No.:	DEKRA-T5F-003	**Expiration:**	2028/07/19		

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The organization, facilities and procedures have been assessed by the IECQ Certification Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of ISO/IEC 17025:2017 for the testing of component product under the IECQ.

Scope:

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Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

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See attached Schedule of Scope

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-- Attached Schedule: IECQ-L DEKRA 16.0002-05-S.pdf --

Approved by Certification Body (CB): DEKRA Certification B.V.

Meander 1051
Arnhem
Netherlands

Authorized person:

Ted Gaertner

DEKRA

The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.
This Certificate of Conformity may be suspended or withdrawn in accordance with the Rules of Procedure of the IECQ System and its Schemes.
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-- Attached Translation: - None --

Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002-05

CB Certificate No.: DEKRA-T5F-003

Schedule Number: IECQ-L DEKRA 16.0002-05-S **Rev No.:** 1 **Revision Date:** 2025/07/20 **Page** 1 **of** 1

Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard
High Temperature Operation test (HTOL)	JESD22-A108, AEC-Q100, AEC-Q200, MIL-STD-202
Low Temperature Operating Life (LTOL)	JESD22-A108
High Temperature Forward Bias (HTFB)	JESD22-A108
High Temperature Gate Bias (HTGB)	JESD22-A108, AEC-Q101
High Temperature Reverse Bias (HTRB)	JESD22-A108, AEC-Q101, MIL-STD-750, MIL-STD-883
Early Life Failure Rate (ELFR)	JESD22-A108, AEC-Q100
Highly Acclerated Stress Test (HAST)	JESD22-A110, AEC-Q100, AEC-Q101
Steady-Status Temperature and Humidity Bias Life Test (THB)	JESD22-A101, AEC-Q100, AEC-Q101, AEC-Q200, MIL-STD-202
Power and Temperature Cycling (PTC)	JESD22-A105, AEC-Q100, AEC-Q101
Electromigration (EM)	JEP001, JESD61, JESD87, AEC-Q100,
Stress Migration (SM)	JEP001, JEP139, JESD87, AEC-Q100,
Steady-Status operation life	MIL-STD-750, MIL-STD-883
Solderability test	J-STD-020, JESD22-B102